

What is claimed is:

1. A test method of a memory IC function, comprising the following steps of:

preparing a memory tester;

preparing memory ICs of different types;

transmitting data related to each test method of these memory ICs to the memory tester;

generating a random number;

executing a test of a predetermined memory IC in reply to the generated random number; and

judging whether the tests of all the memory ICs are finished or not; repeating the generation of the random number and the execution of the test when they are not finished; and finishing the processing when they are finished.

2. The test method of a memory IC function, according to Claim 1, wherein

the random number is arbitrary integer from 0 to 255.

3. The test method of a memory IC function, according to Claim 1, wherein

the memory IC includes Flash ROM, DRAM, and SDRAM.

4. The test method of a memory IC function, according to Claim 1, comprising

a step of performing timer interruption processing after execution of the test of the memory IC.

5. The test method of a memory IC function, according

to Claim 4, wherein

the timer interruption processing is performed with a predetermined cycle.

6. The test method of a memory IC function, according to Claim 5, wherein

the predetermined cycle is defined by the millisecond.

7. A test method of a memory IC function, comprising the following steps of:

preparing a memory tester;

preparing ICs of different types;

transmitting data related to each test method of these ICs to the memory tester;

generating a random number;

executing a test of a predetermined IC in reply to the generated random number; and

judging whether the tests of all the ICs are finished or not; repeating the generation of the random number and the execution of the test when they are not finished; and finishing the processing when they are finished.

8. The test method of a memory IC function, according to Claim 7, wherein

the random number is arbitrary integer from 0 to 255.

9. The test method of a memory IC function, according to Claim 7, wherein

the IC includes a memory IC, a communication interface

IC, and a CPU peripheral IC.

10. The test method of a memory IC function, according to Claim 9, wherein

the memory IC includes Flash ROM, DRAM, and SDRAM.

11. The test method of a memory IC function, according to Claim 9, wherein

the communication interface IC is an IC including UART interface and USB interface.

12. The test method of a memory IC function, according to Claim 9, wherein

the CPU peripheral IC is an IC including DMAC.

13. The test method of a memory IC function, according to Claim 7, comprising

a step of performing timer interruption processing after execution of the test of the memory IC.

14. The test method of a memory IC function, according to Claim 13, wherein

the timer interruption processing is performed with a predetermined cycle.

The test method of a memory IC function, according to Claim 5, wherein

the predetermined cycle is defined by the millisecond.